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	11317530	16-11-99	Japan (abstract)			YES	NO
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	2 T-	King et al., J. Electron	chem. Soc., 14	1(8) 2235-41 (1994)			<del></del>	
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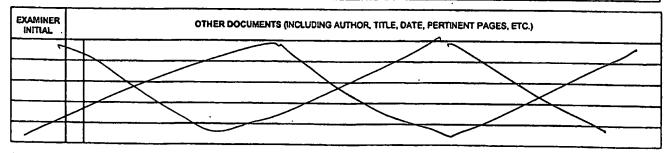
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BY APPLICANT APPLICANT Michael A. Todd 2 8 2004 (USE) SEVERAL SHEETS IF NECESSARY) FILING DATE February 11, 2002 GROUP . 2812 U.S. PATENT DOCUMENTS

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